

KSC2751

High Speed High Current Switching Industrial Use



NPN Epitaxial Silicon Transistor

Absolute Maximum Ratings T_C=25°C unless otherwise noted

Symbol	Parameter	Value	Units
V _{CBO}	Collector-Base Voltage	500	V
V _{CEO}	Collector-Emitter Voltage	400	V
V _{EBO}	Emitter-Base Voltage	7	V
I _C	Collector Current (DC)	15	А
I _{CP}	*Collector Current (Pulse)	30	А
I _B	Base Current (DC)	7.5	А
P _C	Collector Dissipation (T _C =25°C)	120	W
T _J	Junction Temperature	150	°C
T _{STG}	Storage Temperature	- 55 ~ 150	°C

^{*} PW≤300μs, Duty Cycle≤10%

Electrical Characteristics T_C=25°C unless otherwise noted

Symbol	Parameter	Test Condition	Min	Тур	Max	Units
V _{CEO} (sus)	Collector-Emitter Sustaining Voltage	$I_C = 10A$, $I_{B1} = 2A$, $L = 50\mu H$	400			V
V _{CEX} (sus)1	Collector-Emitter Sustaining Voltage	$I_C = 10A$, $I_{B1} = -I_{B2} = 2A$ $T_C = 125$ °C, $I = 180\mu H$, Clamped	450			V
V _{CEX} (sus)2	Collector-Emitter Sustaining Voltage	$I_C = 20A$, $I_{B1} = 4A$, $-I_{B2} = 2A$ $T_C = 125$ °C, $L = 180\mu$ H,Clamped	400			V
I _{CBO}	Collector Cut-off Current	$V_{CB} = 400V, I_{E} = 0$			100	μΑ
I _{CER}	Collector Cut-off Current	$V_{CE} = 400V, R_{BE} = 50\Omega$ @ $T_{C} = 125^{\circ}C$			2	mA
I _{CEX1}	Collector Cut-off Curren	$V_{CE} = 400V, V_{BE}(off) = -1.5V$			100	μΑ
I _{CEX2}	Collector Cut-off Current	$V_{CE} = 400V, V_{BE}(off) = -1.5V @ T_{C} = 125\Omega$			1	mA
I _{EBO}	Emitter Cut-off Current	$V_{EB} = 5V, I_{C} = 0$			10	μΑ
h _{FE1} h _{FE2} h _{FE3}	* DC Current Gain	$V_{CE} = 5V, I_{C} = 2A$ $V_{CE} = 5V, I_{C} = 5A$ $V_{CE} = 5V, I_{C} = 10A$	15 10 7	35	80	
V _{CE} (sat)	* Collector-Emitter Saturation Voltage	I _C = 10A, I _B = 2A		0.3	1	V
V _{BE} (sat)	* Base Emitter ON Voltage	I _C = 10A, I _B = 2A		1	1.5	V
t _{ON}	Turn ON Time	$V_{CC} = 150V, I_{C} = 10A$			1	μs
t _{STG}	Storage Time	$I_{B1} = -I_{B2} = 2A$			2.5	μs
t _F	Fall Time	$R_L = 15\Omega$			0.7	μs

^{*} Pulse Test: PW≤350μs, Duty Cycle≤2% Pulsed

h_{FE} Classificntion

Classification	N	R	0	Y
h _{FE1}	15 ~ 30	20 ~ 40	30 ~ 60	40 ~ 80

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Typical Characteristics

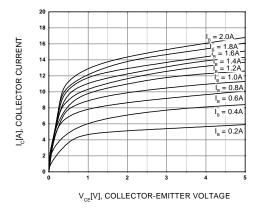


Figure 1. Static Characteristic

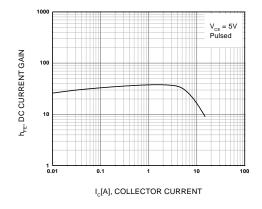


Figure 2. DC current Gain

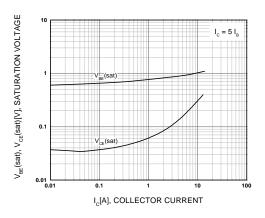


Figure 3. Base-Emitter Saturation Voltage Collector-Emitter Saturation Voltage

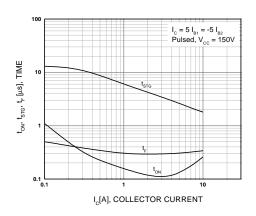


Figure 4. Switching Time

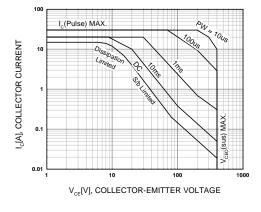


Figure 5. Safe Operating Area

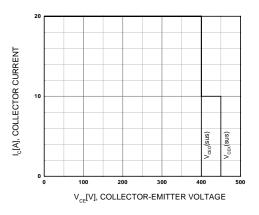
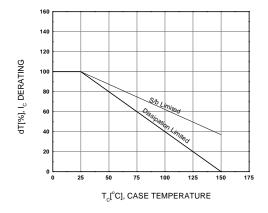


Figure 6. Reverse Bias Safe Operating Area

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Typical Characteristics (Continued)



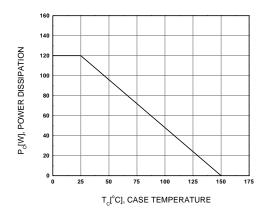


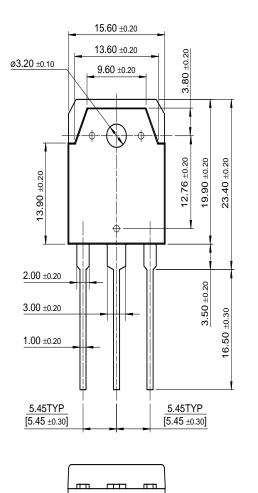
Figure 7. Derating Curve of Safe Operating Area

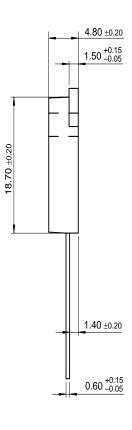
Figure 8. Power Derating

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Package Demensions

TO-3P





Dimensions in Millimeters

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